Special Issue

Explainable Machine Learning and Computer Vision

Message from the Guest Editors

Explainable machine learning and computer vision are essential for building transparent, trustworthy artificial intelligence that can be used in critical domains, such as medical imaging, autonomous driving, and industrial inspection, where understanding the model's decisions is key for safety, fairness, and compliance. The goal of this Special Issue is to compile papers on the methods, evaluations, and applications that make machine learning and computer vision-based artificial intelligence systems interpretable and accountable. Topics relevant to this Special Issue include those listed in the keywords below: Saliency and feature attribution; Counterfactual and concept explanation methods; Model-agnostic approaches; Metrics and benchmarks for explainability; Human-centered evaluation of interpretability; Explainability in video, 3D vision, and multimodal tasks: Integration of explainable Al into visualization dashboards and reporting.

Guest Editors

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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

Editor-in-Chief

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